## Search Notes

| Application/Control No. | Applicant(s)/Patent under Reexamination |
|---|---|
| 10/669,997 | DIDIER ET AL. |
| **Examiner** | **Art Unit** |
| Paul D. Kim | 3729 |

### SEARCHED

| Class | Subclass | Date | Examiner |
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| 310 | 179<br>208 | | |
| 72 | 70,131<br>203 | | |
| | 275,294 | | |
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| Class | Subclass | Date | Examiner |
|---|---|---|---|
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| PGPub Text Search | | 10/28/2005 | PK |

### SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|---|---|---|
| Texe Search<br>EAST/NPL (IEEE) | 10/27/2005 | PK |
| PGPub Text Search<br>EAST | 10/28/2005 | PK |
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